

IN THE SPECIFICATION~~PBEST AVAILABLE COPY~~

Please amend the portions of the Specification identified below to read as indicated herein.

Paragraph starting at Page 1, line 8:

In particular, interferometric measurements employing interferometers (such as e.g. Michelson or other interferometers) have been found to be highly susceptible ~~for to~~ mechanical disturbances such as vibration or shock even caused by sound.

Paragraph starting at page 1, line 16:

According to the present invention, a measurement setup for measuring an optical device under test (DUT) is provided comprising a measurement unit with reduced susceptibility to mechanical noise such as e.g. sound or vibration. The measurement unit comprises an optical circuit with such optical components showing high susceptibility to mechanical noise. Such components might in particular comprise interferometers. The optical circuit is provided in a casing providing a shielding against mechanical noise. Preferably the casing is provided with relatively high weight, thus rendering the casing less susceptible to be ~~excited~~ excited by mechanical vibrations. The casing might therefore comprise mass plates or be entirely of a material massive relative to the optical circuit or its components.